

**AMENDMENTS TO THE CLAIMS**

The following listing of claims will replace all prior versions, and listings of claims in the application:

**Listing Of Claims:**

1. (Currently Amended) A method for testing ~~pre-designated~~ configuration space settings ~~in~~ of a chip, comprising the steps of:

providing a main board including a chip to be tested, the chip having a ~~pre-designated~~ configuration space defined therein;

providing a BIOS program including a configuration space setting test process therein;

starting power for said main board;

performing a power-on self-test;

loading said BIOS program; and

executing said configuration space setting test process to verify test correspondence of said configuration space defined in said chip to ~~for~~ the ~~pre-designated~~ configuration space settings ~~in~~ of said chip.

2. (Previously Presented) The method according to Claim 1, wherein said configuration test process included in said BIOS program comprises the steps of:

providing a test datum;

providing an expected result datum corresponding to said test datum;

inputting said test datum into said BIOS;  
enabling a register corresponding to said chip configuration space  
depending on said test datum;  
triggering said chip to perform the corresponding operation;  
obtaining a result that is produced after operation of said chip; and  
comparing said obtained result datum with said expected result  
datum.

3. (Previously Presented) The method according to Claim 2, further comprising the step of recording said comparison result.

4. (Previously Presented) The method according to Claim 3, further comprising the step of generating a difference report.

5. (Previously Presented) The method according to Claim 1, wherein said configuration test process included in said BIOS program comprises the steps of:

providing at least one set of test data;  
providing at least one set of expected result data corresponding to  
said test data;  
inputting said test data;

enabling a register corresponding to said chip configuration space depending on said test data;

obtaining corresponding result data after operating of said chip in accordance with said test data; and

comparing said obtained result data with said corresponding expected result data.

6. (Previously Presented) The method according to Claim 5, wherein said test data is implemented in the form of a data table list.

7. (Previously Presented) The method according to Claim 5, wherein said expected result data is implemented in the form of a data table list.

8. (Previously Presented) The method according to Claim 5, further comprising the step of recording said comparison results

9. (Previously Presented) The method according to Claim 8, wherein said records of said comparison results are implemented in the form of a data table list.

10. (Previously Presented) The method according to Claim 9, wherein each of said records of said comparison results includes a result and difference obtained from said comparison.
11. (Previously Presented) The method according to Claim 5, further comprising the step of generating a test report.
12. (Previously Presented) The method according to Claim 10, further comprising the step of generating a difference report.